

Beam Test analysis - spatial resolution

Cheng-Wei Shih,
National Central University/RIKEN

Aug 1st, 2025
INTT meeting



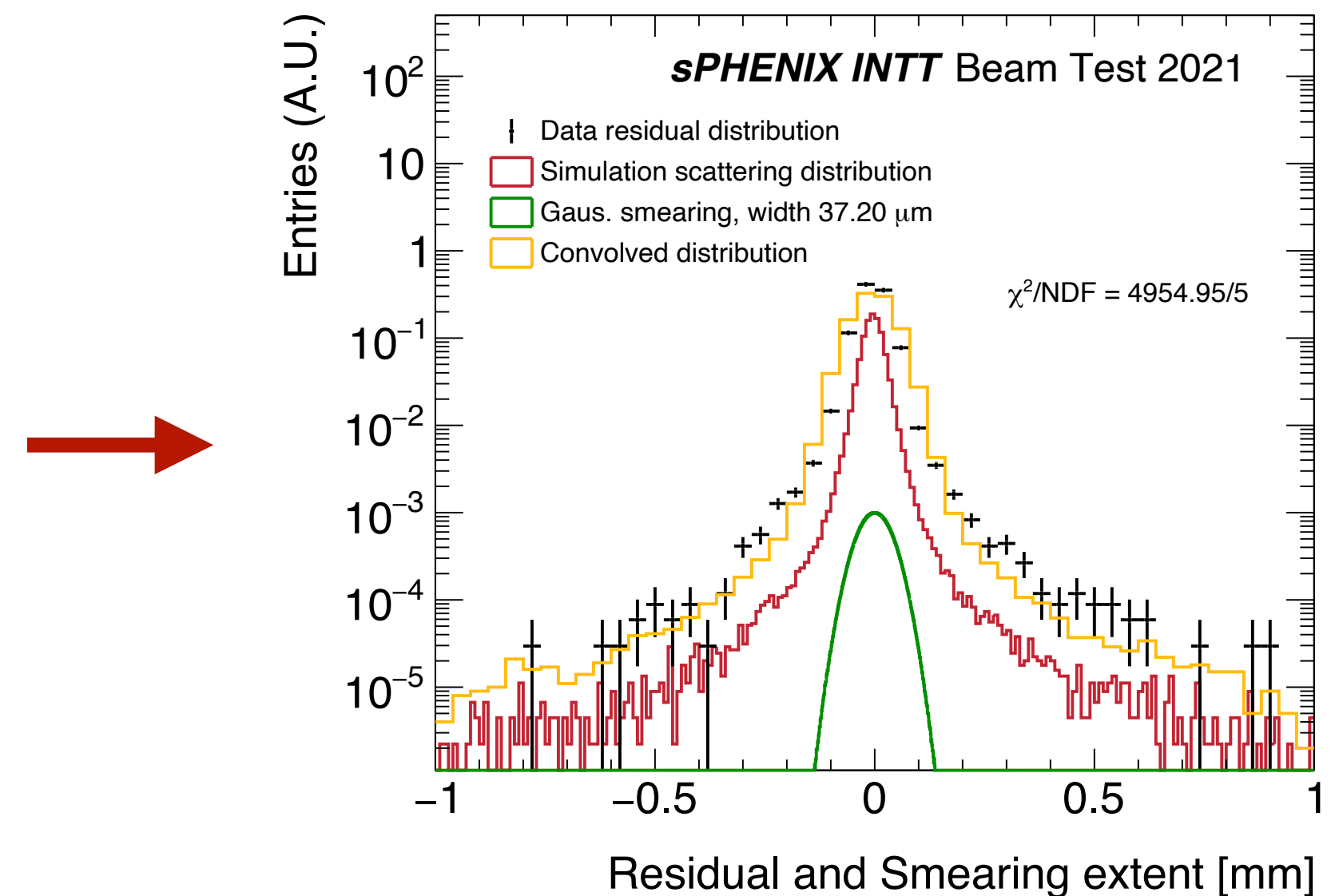
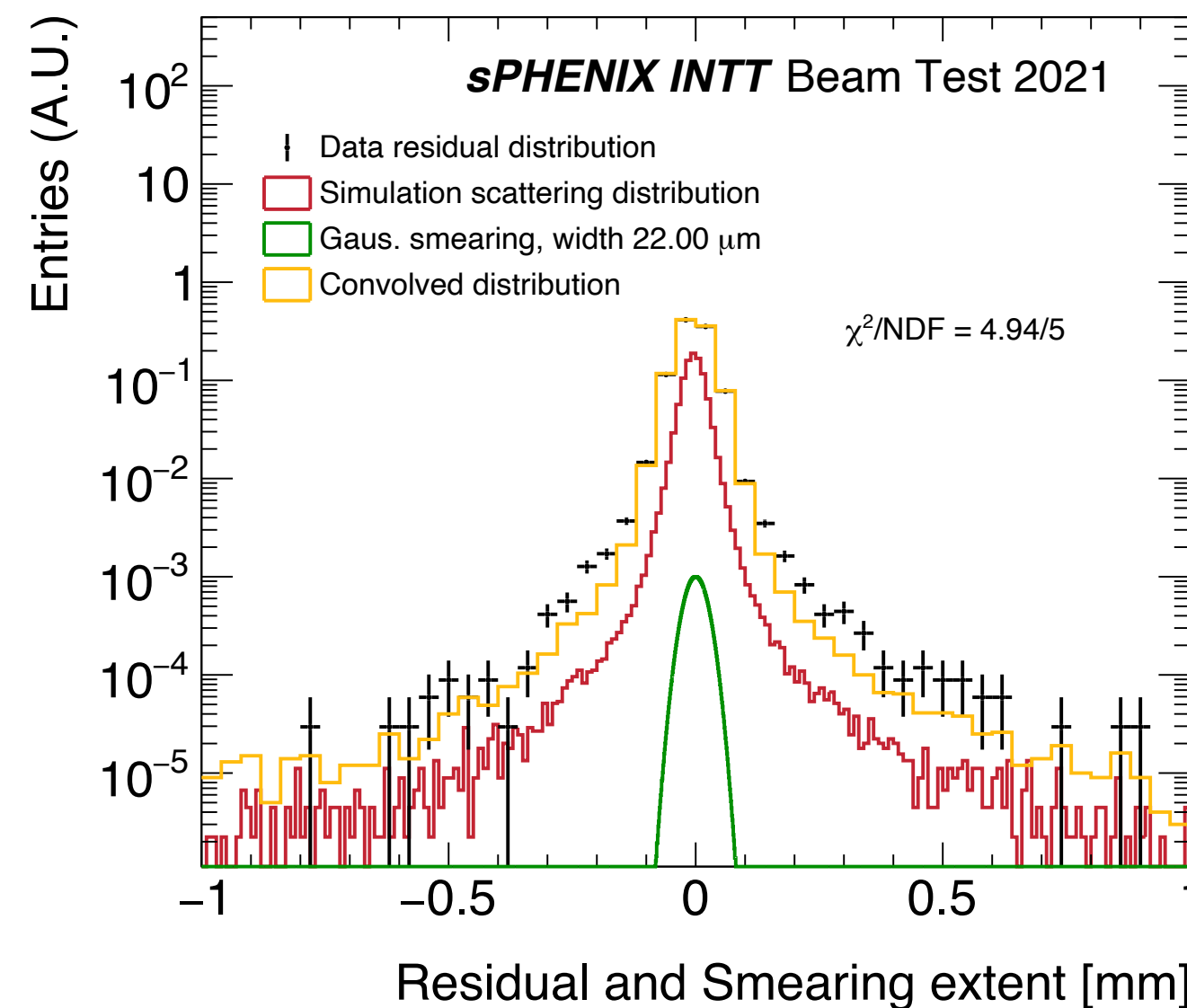
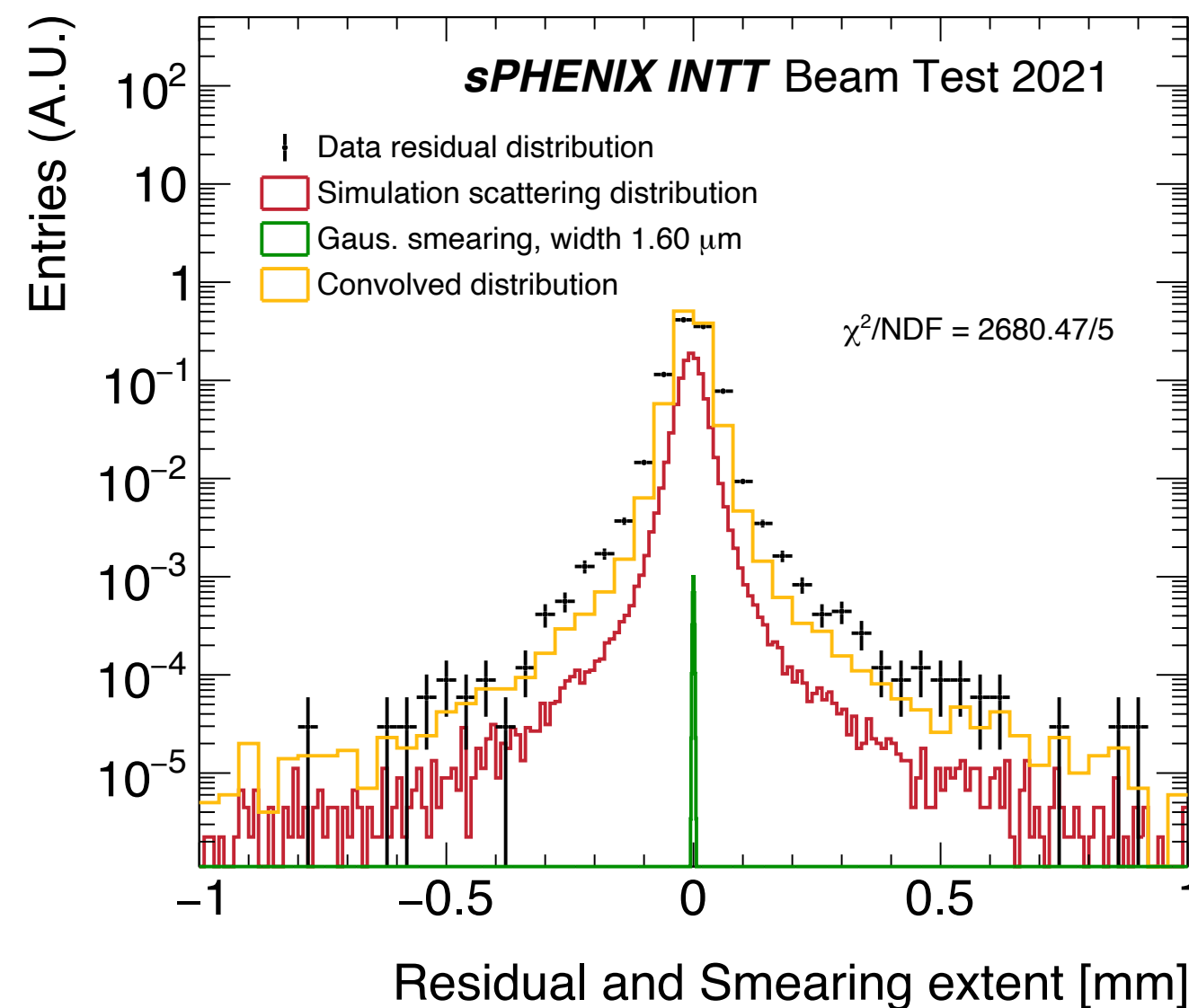
國立中央大學
National Central University

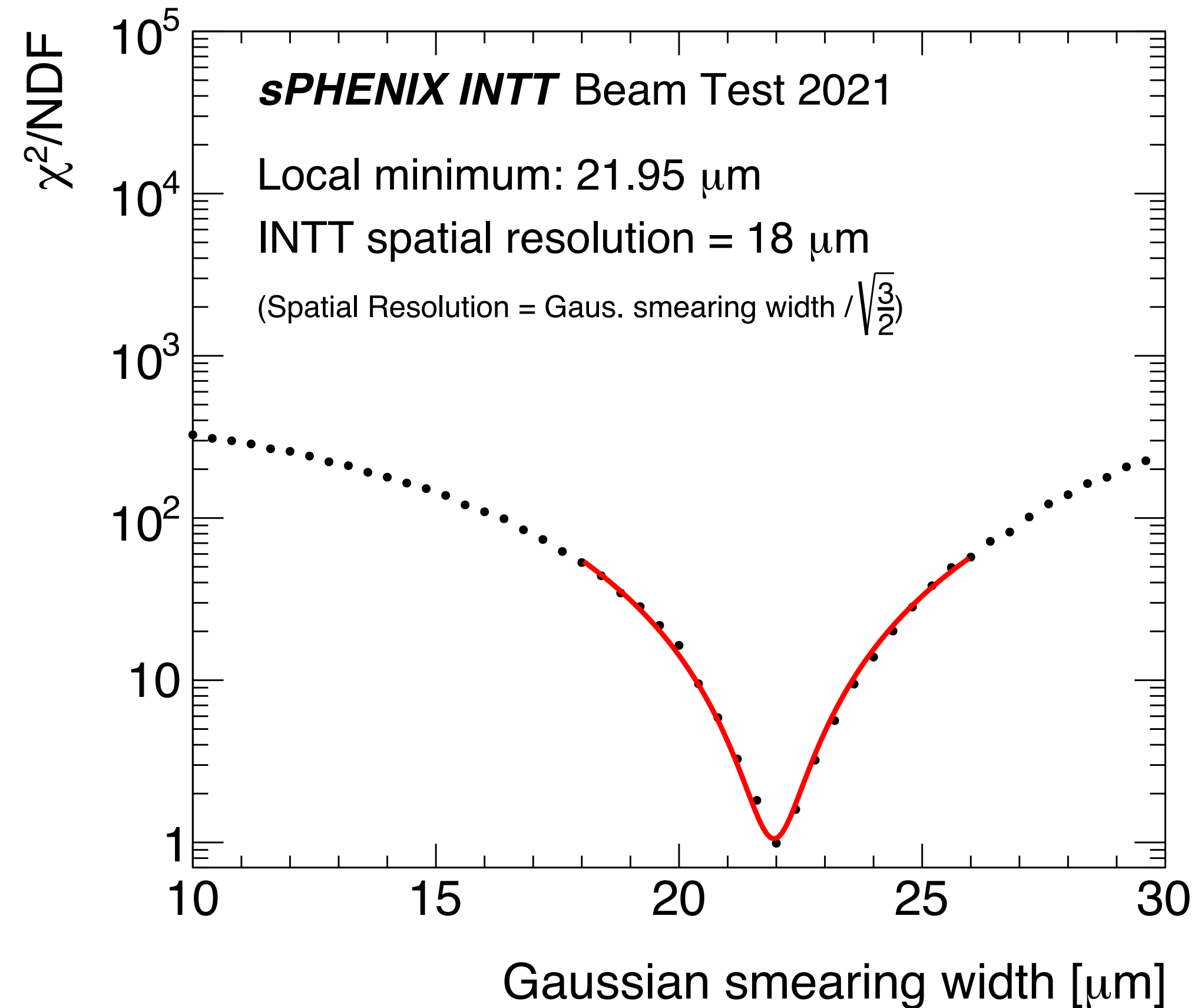


- Expected binary INTT hit spatial resolution = $78 \mu\text{m}/\sqrt{12} = 22.52 \mu\text{m}$
- The measured residual distribution = the convolution of
 - Residual distribution of multiple Coulomb scattering distribution σ_{MS}
 - Spatial resolution of the reconstructed track σ_{track} (L0-L2 interpolation)
 - Spatial resolution of the device under test (DUT) σ_{Ladder} (ladder L1)
- $\sigma_{\text{measured}}^2 = \sigma_{MS}^2 + \sigma_{\text{track}}^2 + \sigma_{\text{Ladder}}^2$
 - This is not a mathematical expression, but more like a concept, as the residual distributions are not a Gaussian distribution
- $\sigma_{\text{track}}^2 = k \cdot \sigma_{\text{plane}}^2$, $k = \frac{\sum_i^N z_i^2}{N \sum_i^N z_i^2 - (\sum_i^N z_i)^2}$, where z_i is the plan location in the beam direction
 - Assuming the layers used for the track reconstruction have the same spatial resolution
 - If the track layers are symmetrically distributed on both sides of the DUT $\rightarrow k = 1/N$
 - For the case of INTT telescope, $\sigma_{\text{track}}^2 = \frac{1}{2} \sigma_{\text{plane}}^2 = \frac{1}{2} \sigma_{\text{Ladder}}^2$ (track layers are identical to the DUT. And layers are placed symmetrically)
- **For the INTT beam test, the measured residual distribution = convolution of pure scattering distribution (σ_{MS}) and a Gaussian distribution ($\sigma_{\text{track}} + \sigma_{\text{Ladder}}$) with the Gaussian width of $\frac{3}{2} \sigma_{\text{Ladder}}^2$**

INTT hit spatial resolution

- For the INTT beam test, the measured residual distribution = convolution of pure scattering distribution (σ_{MS}) and a Gaussian distribution ($\sigma_{track} + \sigma_{Ladder}$) with the Gaussian width of $\frac{3}{2}\sigma_{Ladder}^2$
- Approach:
 - Prepare the residual distribution of multiple Coulomb scattering from simulation
 - Convolve the distribution with a Gaussian distribution with different width
 - Quantify the agreement between the data residual distribution and the convolved distribution by the chi-square test
 - σ_{Ladder} = width of the best matched Gaussian distribution / $\sqrt{3/2}$





Best matched Gaussian width (local minimum) = $\frac{3}{2}\sigma_{\text{Ladder}}^2 \rightarrow$ INTT spatial resolution of 18 μm is observed using beam test data

It is better than its binary spatial resolution (22.52 μm), attributed from the charged sharing, and the 3-bit adc of the FPHX chip

- <https://link.springer.com/article/10.1007/s41365-024-01447-9>